

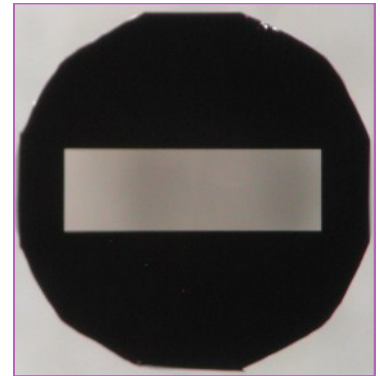
ULTRATHIN RECTANGULAR SILICON NITRIDE WINDOWS

Applications: Tomography, high resolution TEM

Electron Tomography (ET) is used to obtain three-dimensional (3D) information about nanoscale objects. Ability to acquire data over sufficient tilt range is one of the most critical factors in ET.

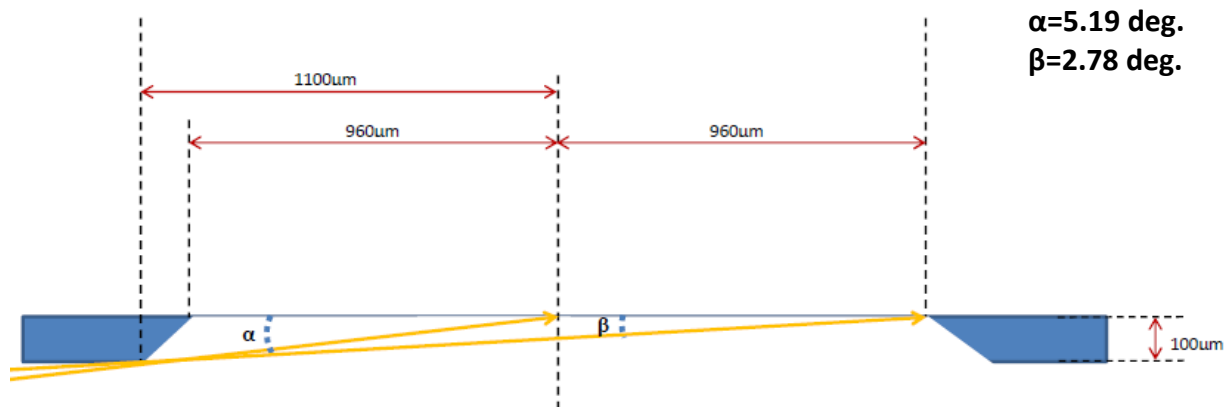
In general, normal TEM grids have a maximum tilt angle of about 60 degrees before the grid bars block the beam, while Norcada high tilt tomography windows can tilt up to 85 degrees, which is practically comparable to 90 degrees tilt.

Our robust and ultrathin Silicon Nitride membranes are suitable for all standard TEM samples which can be prepared on TEM grids. These devices have a 2.85mm Diameter, 100 μ m thick Silicon frame.



Front view of a N1S1906A TEM window device

Part Number	Window Size	Nitride Thick.	Number of Windows	Tilt Angle (see schematic)
N1S1906A	1.9x0.6mm	50nm	1	87 $^{\circ}$
N2S1801A	1.8x0.1mm	50nm	2	84 $^{\circ}$



Tilt angle calculation of N1S1906A TEM window device